

# MSP120N08G

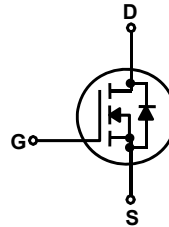
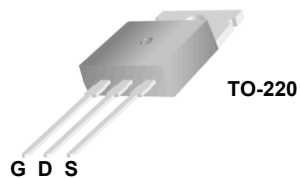
## 80V N-Channel MOSFET

### General Description

This Power MOSFET is produced using Maple semi's advanced technology, which provides high performance in on-state resistance, fast switching performance and excellent quality. MSP120N08G suitable device for Synchronous Rectification For Server and general purpose applications.

### Features

- 120A, 80V,  $R_{DS(TYP)} = 5.5m\Omega @ V_{GS} = 10V$
- Low gate charge ( typical 59 nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability



### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	MSP120N08G	Units
$V_{DSS}$	Drain-Source Voltage	80	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 100^\circ\text{C}$ )	120	A
		67	A
$I_{DM}$	Drain Current - Pulsed (Note 1)	420	A
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
EAS	Single Pulsed Avalanche Energy (Note 2)	144.5	mJ
$I_{AR}$	Avalanche Current (Note 1)	120	A
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	157	W
		1.26	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

\* Drain current limited by maximum junction temperature.

### Thermal Characteristics

Symbol	Parameter	MSP120N08G	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.8	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	$^\circ\text{C}/\text{W}$

**Electrical Characteristics** $T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	80	--	--	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.1	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 64\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	$\mu\text{A}$
		$V_{DS} = 64\text{ V}, T_C = 125^\circ\text{C}$	--	--	10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	2.0	--	4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 60\text{ A}$	--	5.5	7.0	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 10\text{ V}, I_D = 60\text{ A}$ (Note 3)	--	47	--	S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	3841	--	pF
$C_{oss}$	Output Capacitance		--	652	--	
$C_{rss}$	Reverse Transfer Capacitance		--	34	--	

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DS} = 40\text{ V}, I_D = 60\text{ A},$ $R_G = 3.0\text{ }\Omega$ (Note 3, 4)	--	15.6	--	ns
$t_r$	Turn-On Rise Time		--	32.7	--	
$t_{d(off)}$	Turn-Off Delay Time		--	24.2	--	
$t_f$	Turn-Off Fall Time		--	15.1	--	
$Q_g$	Total Gate Charge	$V_{DS} = 40\text{ V}, I_D = 60\text{ A},$ $V_{GS} = 10\text{ V}$ (Note 3, 4)	--	59.4	--	nC
$Q_{gs}$	Gate-Source Charge		--	16.5	--	
$Q_{gd}$	Gate-Drain Charge		--	12.3	--	

**Drain-Source Diode Characteristics and Maximum Ratings**

$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 60\text{ A}$	--	0.9	1.2	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{ V}, I_S = 60\text{ A},$	--	64.3	--	ns
$Q_{rr}$	Reverse Recovery Charge	$di_F / dt = 100\text{ A}/\mu\text{s}$ (Note 3)	--	152.7	--	$\mu\text{C}$

**Notes:**

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2.  $I_{AS} = 17\text{ A}, L = 1.0\text{ mH}, V_{GS} = 10\text{ V}$ , Starting  $T_J = 25^\circ\text{C}$
3. Pulse Test : Pulse width  $\leq 300\text{ }\mu\text{s}$ , Duty cycle  $\leq 2\%$
4. Essentially independent of operating temperature

### Typical Characteristics

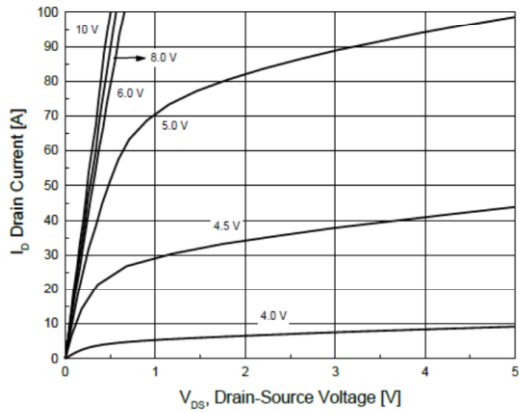


Figure 1. On-Region Characteristics

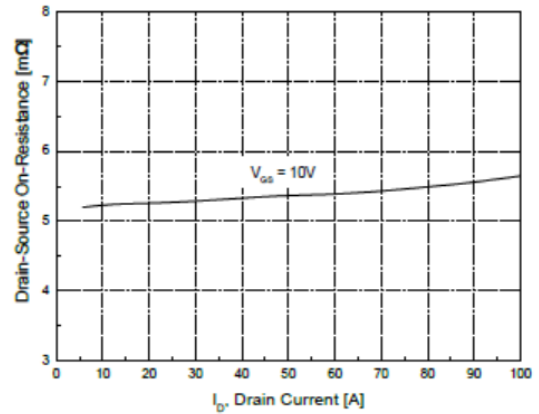


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

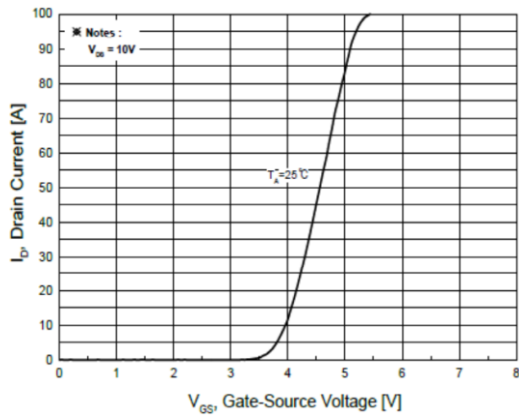


Figure 3. Transfer Characteristics

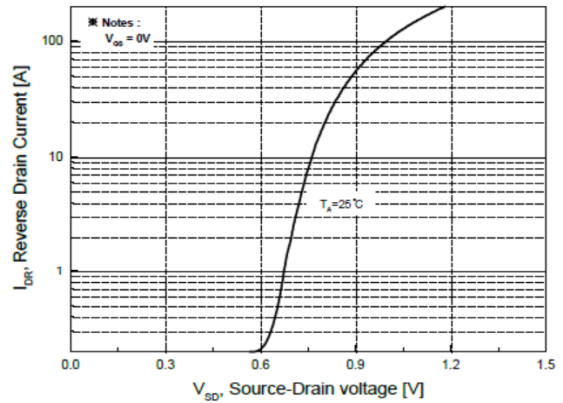


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

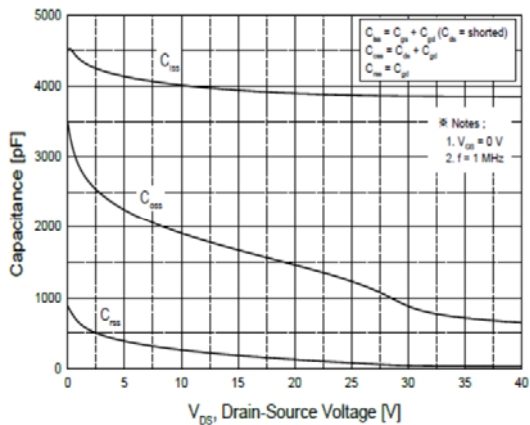


Figure 5. Capacitance Characteristics

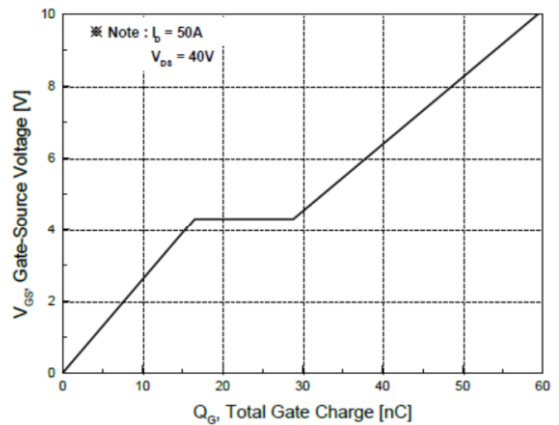


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

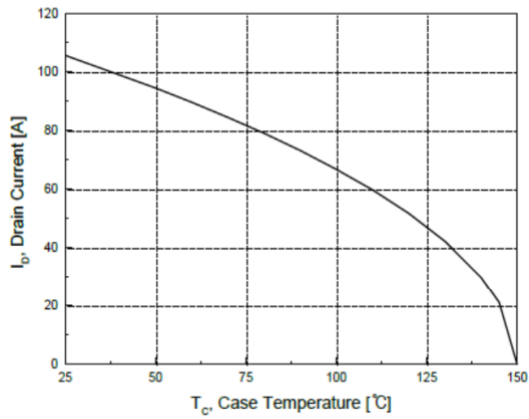


Figure 7. Maximum Drain Current VS Case Temperature

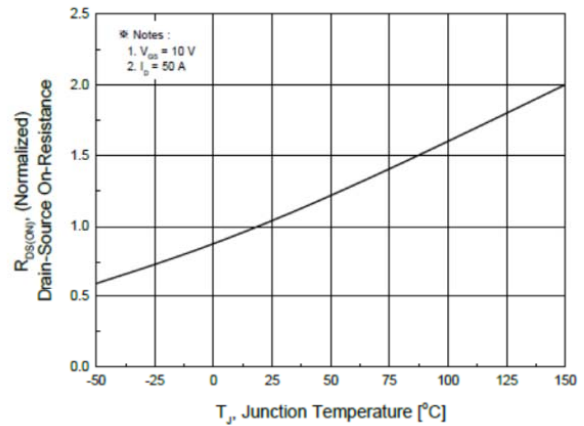


Figure 8. On-Resistance Variation vs Temperature

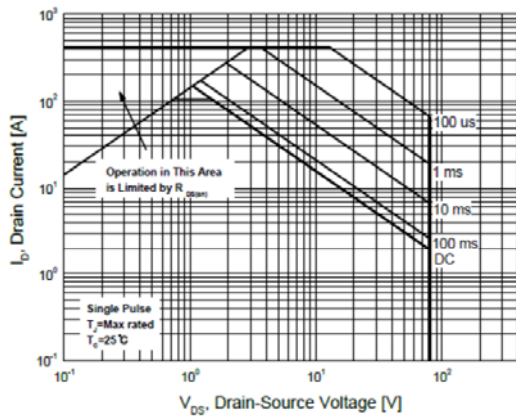


Figure 9. Maximum Safe Operating Area

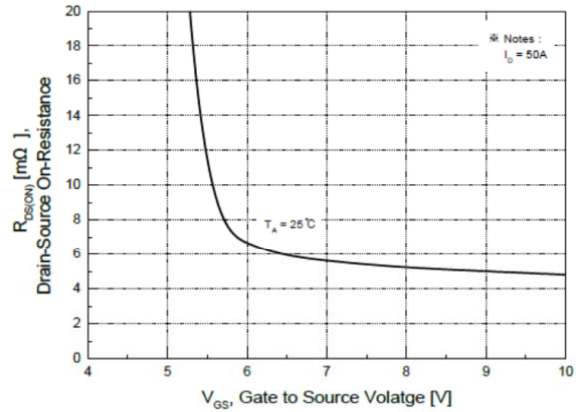


Figure 10. On-Resistance Variation with Gate to Source Voltage

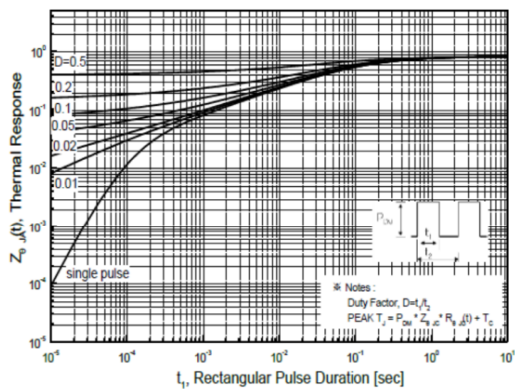
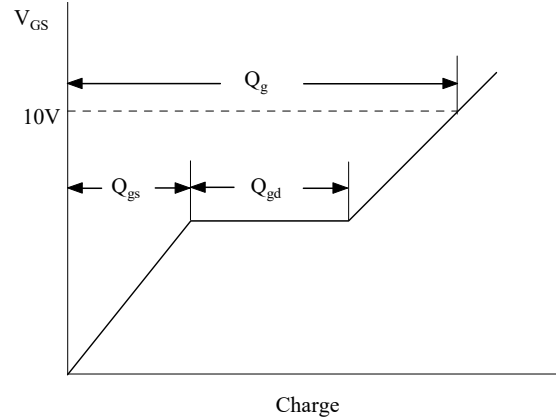
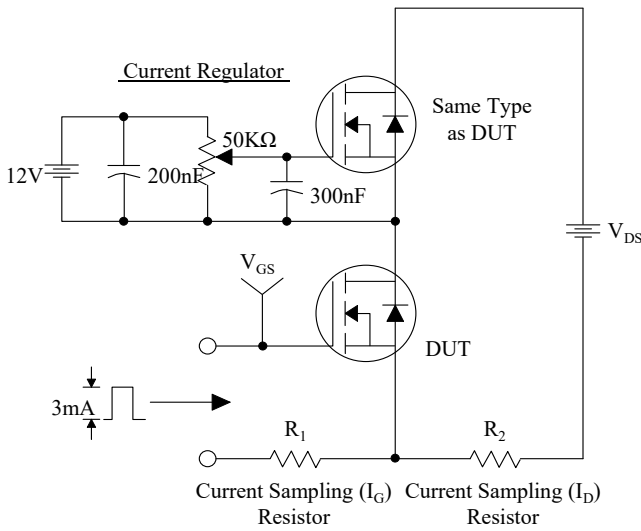
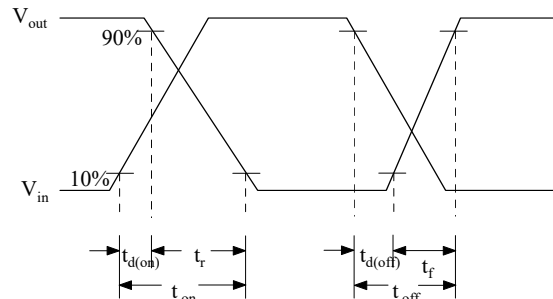
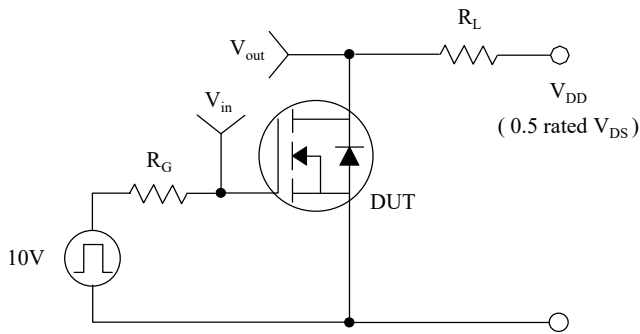


Figure 11. Transient Thermal Response Curve

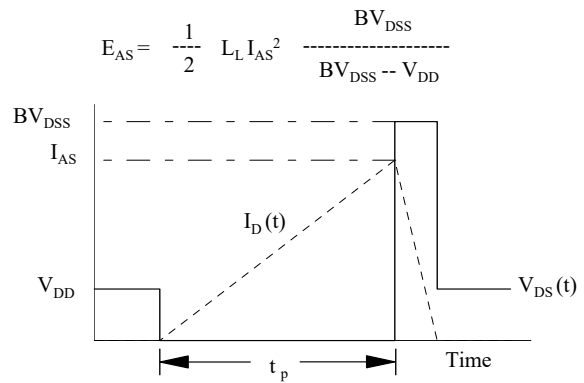
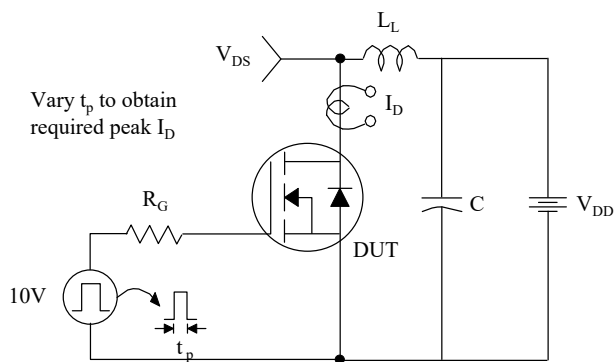
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



### Peak Diode Recovery dv/dt Test Circuit & Waveforms

